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of deposit as the filing date. Depositor: KAREN CINQ-MARS

Karen Cinq-Mars 7/29/03
(Signature & date)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of _____: 7/29/03

Wei Lu, et al. _____ Group Art Unit:

Serial No. 10/604,110 _____: Examiner:

Filed: 6/26/03 International Business
Machines Corporation
2070 Route 52
Hopewell Junction, NY 12533

TITLE: METROLOGY PROCESS FOR ENHANCING IMAGE CONTRAST

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents
Alexandria, VA 22313-1450

Sir:

Pursuant to the duty of disclosure set forth in 37 C.F.R. 1.56, and further pursuant to the provisions of 37 C.F.R. 1.97 and 1.98, applicants hereby respectfully submit copies of the prior patents and publications as listed on Form PTO-1449, attached hereto.

In citing these documents, no representation is made nor intended as to the pertinency or non-pertinency of the art, that better art than that listed is not available, or that other art is not applicable.

Respectfully submitted,
Wei Lu, et al.

By Tiffany L. Townsend
Tiffany L. Townsend, Attorney
Registration No. 43,199
Telephone No. 845-894-3668

**INFORMATION DISCLOSURE CITATION***(Use several sheets if necessary)*

Docket Number (Optional)

FIS920030143US1

Application Number

Applicant(s)

WEI LU, ET AL.

Filing Date

6/26/03

Group Art Unit

U.S. PATENT DOCUMENTS

| *EXAMINER INITIAL | REF | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|----------------------|-----|-----------------|----------|-----------------|-------|----------|-------------------------------|
| | | 2002/0195422A1 | 12/26/02 | SIEVERS, ET AL. | | | |
| | | 2002/0019137A1 | 2/14/02 | TSUNG, ET AL. | | | |
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FOREIGN PATENT DOCUMENTS

| | REF | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | Translation | |
|--|-----|-----------------|------|---------|-------|----------|-------------|----|
| | | | | | | | YES | NO |
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OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

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EXAMINER**DATE CONSIDERED**

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.